



DOCUMENT CHANGE REQUEST

DCR number 1429 Changes required for: General
Date: 2021/06/25 Date sent: 2021/05/27
Status: IMPLEMENTED

Originator: Steve Thacker
Organisation: ESCC Executive Secretariat

Title: The ESCC Documentation System

Number: 12001 Issue: 4

Other documents affected:

20400-4, 2263503-1, 24700-3, 25200-3

Page:

As applicable

Paragraph:

As applicable; see also below

Original wording:

As per current issue

Proposed wording:

Due to the retirement of ESCC ancillary sectional basic specs 2049000 & 2059000 (See DCRTBA as raised 27/05/21), the following changes are necessary to reflect the fact that references to these 2 specs will be obsolete:

....

ESCC 12001:

Para. 7.4, Change 3rd example from 2049000 to:

"2045000 is the Basic Specification for internal visual inspection of discrete, non-microwave semiconductors and is an Ancillary Specification."

....

ESCC 20400:

Para. 4

From the listing, delete reference to 2049000 from the list.

Amend note 1 to remove reference to ESCC 2049000 which is replaced by "MIL-STD-883, Test Method 2010, 2013, 2014, 2032, as applicable, should be used to the extent applicable."

....

ESCC 20500:

Para. 4

From the listing, delete reference to 2059000 from the list.

Amend note 2 to remove reference to ESCC 2059000 which is replaced by "MIL-STD-883, Test Method 2009, 2016, as applicable, should be used to the extent applicable."



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ESCC 24700:

Para 5, Page 37:

Delete MIL-STD-883 Test Method 2009 section in full.

Para 5, Page 38:

Under MIL-STD-883 Test Method 2010:

delete sub-paragraph "ESCC 20400 - ESCC 20400, supported by ESCC 2049000 ... etc"

under sub-paragraph 'Equivalence Status', delete "MIL-STD-883, Test Method 2010, is equivalent to ESCC 20400/2049000"

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ESCC 25200:

Para 2.1: delete "No. 2049000, Internal Visual Inspection of Integrated Circuits."

Para 5.3.3: delete "(see ESCC No. 2049000)"

Para 7.4: replace "(ESCC No. 2049000 and 2099000)" by "(MIL-STD-883 Test Method 2010 and ESCC No. 2099000)"

Para 7.5: replace "(ESCC No. 2049000 and 2099000)" by "(MIL-STD-883 Test Method 2010 and ESCC No. 2099000)"


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ESCC 2263503:

Para 7.3.5.7: replace "ESCC Basic Specification No. 20400, and ancillary specifications 2049000" by "MIL-STD-883, Test Method 2010, 2013, 2014, 2032, as applicable,"

Justification:

As above

Attachments:
N/A
Modifications:
N/A
Approval signature:

Date signed:
2021-06-25